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PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM 10073129	FILING DATE 02/13/2002	CLASS 305	SUBCLASS 200	GAU 2818	EXAMINER DeCady
**APPLICANTS: Sato Masahiro; Akaza Junji; Kodama Nobumi; Mizuno Hirohisa; Imura Takeshi; Matsuzaki Yasuro; 714 / 733 2133 TABONE					
**CONTINUING DATA VERIFIED:					
** FOREIGN APPLICATIONS VERIFIED: JAPAN 2001-199188 06/29/2001					
PG-PUB <input type="checkbox"/> DO NOT PUBLISH <input type="checkbox"/>		RESCIND <input type="checkbox"/>			
Foreign priority claimed <input type="checkbox"/> yes <input type="checkbox"/> no		35 USC 119 conditions met <input type="checkbox"/> yes <input type="checkbox"/> no		ATTORNEY DOCKET NO 108075-00075	
Verified and Acknowledged Examiners's initials					
TITLE : Test apparatus for semiconductor device					
U.S. DEPT. OF COMM./PAT & TM-PTO-436L (Rev. 12-94)					

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Total Claims	
		Print Claim for O.G.	
ISSUE FEE		DRAWING	
Amount Due	Date Paid	Sheet Drwg.	Figs. Drwg.
		Print Fig.	
<input type="checkbox"/> TERMINAL DISCLAIMER		Primary Examiner	
		Application Examiner	
		PREPARED FOR ISSUE	
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